

Search Terms	
1	AMOUNT
2	AMOUNTS
3	AMT
4	AMTS
5	AREA
6	AREAS
7	CONCENTRATION
8	CONCN
9	CONCNS
10	DRIFT
11	DRIFTED
12	DRIFTING
13	DRIFTINGS
14	DRIFTS
15	HEIGHT
16	HEIGHTS
17	IM
18	IMS
19	INTENSITIES
20	INTENSITY
21	INTENSITYS
22	IONISATION
23	IONISATIONS
24	IONIZATION
25	IONIZATIONS
26	MASS
27	MASSES
28	MOBILITIES
29	MOBILITY
30	MOBILITYS
31	PEAK
32	PEAKS
33	QUANTITIES
34	QUANTITY
35	QUANTITYS
36	RATIO
37	RATIOS
38	TIME

	Total	USPAT	US-PGPUB	EPO	JPO	Derwent	IBM TDB	USOCR
1	2752600							
2	814083							
3	326877							
4	62826							
5	2678687							
6	979256							
7	912116							
8	158033							
9	18259							
10	80006							
11	3493							
12	10319							
13	1							
14	12280							
15	952929							
16	146894							
17	36900							
18	4088							
19	70472							
20	503672							
21	6							
22	10978							
23	25							
24	51541							
25	293							
26	793811							
27	59494							
28	6500							
29	99599							
30	1							
31	403628							
32	138401							
33	374955							
34	949596							
35	15							
36	1807143							
37	320345							
38	5405722							

	Search Terms
39	TIMES
40	TIMING
41	TIMINGS
42	WATER
43	WATERS
44	CONCENTRATIONS
45	(((DRIFTED OR DRIFTING OR DRIFT) SAME (TIMING OR TIME)) AND (IMS OR (IONIZATION SAME MOBILITY))) AND (((PEAK SAME RATIO) SAME (INTENSITY OR HEIGHT OR AREA) SAME WATER) SAME (QUANTITY OR MASS OR CONCENTRATION OR AMOUNT)))

	T tal	USPAT	US-PGPUB	EPO	JPO	Derwent	IBM TDB	USOCR
39	1667726							
40	605873							
41	39288							
42	3069550							
43	63234							
44	353295							
45	2	0	0	1	0	1	0	

	U	1	D	Document ID	Issue Date	Pages	Title	Current OR
1	<input type="checkbox"/>	<input type="checkbox"/>	WO 2099405 A2	20021212	15	METHOD FOR MEASURING THE CONCENTRATION OF WATER IN ARGON, HYDROGEN, NITROGEN AND HELIUM BY MEANS OF IONIZATION MOBILITY SPECTROMETRY		
2	<input checked="" type="checkbox"/>	<input type="checkbox"/>	WO 200299405 A	20040303	1	Measurement of water concentration in argon, hydrogen, nitrogen and helium gases, by obtaining signal variable, determining time intervals corresponding to ions drift times and obtaining signal peaks in the time intervals		

	Current XRef	Retrieval Classif	Inventor	S	C	P	2	3	4	5	Image Doc. Displayed	PT
1			PUSTERLA, LUCA et al.	<input checked="" type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	WO 2099405 A2	<input type="checkbox"/>
2			BONUCCI, A et al.	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	EP 1393055 A0	<input type="checkbox"/>

	Search Terms
1	BONUCCI-ANTONIO
2	DRIFT
3	DRIFTS
4	ION
5	PUSTERLA-LUCA
6	STIMAC-ROBERT
7	SUCCI-MARCO
8	WATER
9	WATERS
10	IONS
11	(((((STIMAC-ROBERT.IN.) OR (BONUCCI-ANTONIO.IN.)) OR (PUSTERLA-LUCA.IN.)) OR (SUCCI-MARCO.IN.)) AND DRIFT AND ION AND WATER)

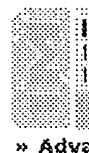
	T tal	USPAT	US-PGPUB	EPO	JPO	Derwent	IBM TDB	USOCR
1	8							
2	80006							
3	12280							
4	627701							
5	11							
6	6							
7	56							
8	3069550							
9	63234							
10	349975							
11	4	0	3	1	0	0	0	

	U	1	Document ID	Issue Date	Pages	Title	Current OR
1	<input type="checkbox"/>	<input type="checkbox"/>	US 20040053420 A1	20040318	12	Method for measuring the concentration of impurities in helium by ion mobility spectrometry	436/171
2	<input checked="" type="checkbox"/>	<input type="checkbox"/>	US 20030209664 A1	20031113	13	Method for measuring the concentration of impurities in nitrogen, hydrogen and oxygen by ion mobility spectrometry	250/282
3	<input checked="" type="checkbox"/>	<input type="checkbox"/>	US 20030201388 A1	20031030	19	Method for measuring the concentration of nitrogen in argon by means of ion mobility spectrometry	250/282
4	<input checked="" type="checkbox"/>	<input type="checkbox"/>	WO 2099405 A2	20021212		METHOD FOR MEASURING THE CONCENTRATION OF WATER IN ARGON, HYDROGEN, NITROGEN AND HELIUM BY MEANS OF IONIZATION MOBILITY SPECTROMETRY	

	Current XRef	Retrieval Classif	Inventor	S	C	P	2	3	4	5	Image Doc. Displayed	PT
1			Pusterla, Luca et al.	<input checked="" type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	US 20040053420	<input type="checkbox"/>
2	250/287		Pusterla, Luca et al.	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	US 20030209664	<input type="checkbox"/>
3	250/287		Pusterla, Luca et al.	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	US 20030201388	<input type="checkbox"/>
4			PUSTERLA, LUCA et al.	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>		<input type="checkbox"/>

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Example: optical <and> (fiber <or> fibre) <in> ti

- 3) Limit the results by selecting Search Options.

- 4) Click Search. See [Search Examples](#)

```
(water<paragraph>concentration
<paragraph>ratio<paragraph>
(peak<or>peaks))
```


Note: This function returns plural and suffixed forms of the keyword(s).

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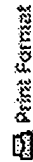
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Namihiro, T.; Tsukamoto, S.; Douyan Wang; Katsuki, S.; Hackam, R.; Akiyama, H.; Uchida, Y.; Koike, M.;
Plasma Science, IEEE Transactions on , Volume: 28 , Issue: 2 , April 2000
Pages: 434 - 442

[Abstract] [PDF Full-Text (220 KB)] IEEE JNL

- 2 **Feasibility of remote underwater current measurement using acoustic doppler techniques**
Emmanuel, C.; Mandics, P.;
OCEANS , Volume: 5 , Sep 1973
Pages: 59 - 63

[Abstract] [PDF Full-Text (472 KB)] IEEE CNF

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